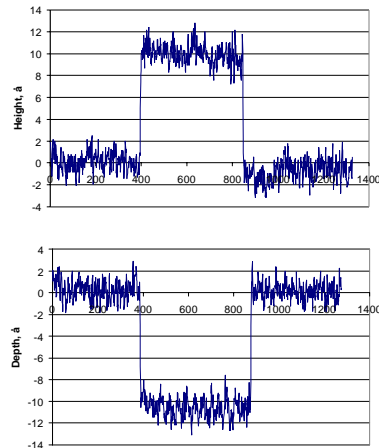
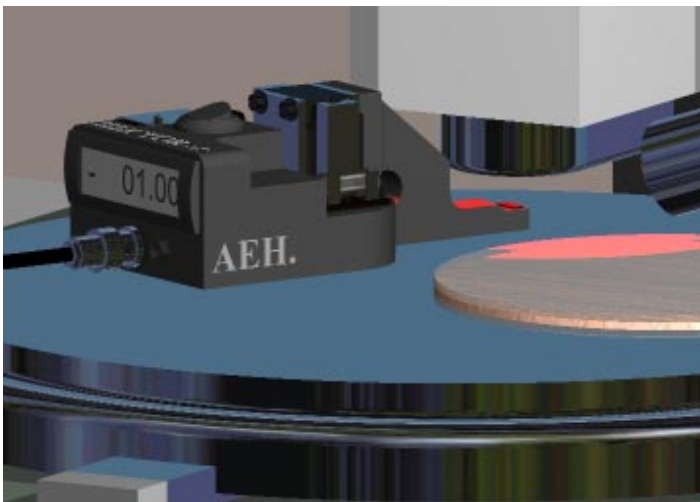


The Calibration Standard for nanometer metrology.

HECTOR-100tm

supports the new Chapter 7, “Nanometer Surface Texture and Step Height Measurements,” in ASME B46.1-2002, the American National Standard for surface texture measurement.



Nanometer-sized step and groove artifacts.

Repeatable and traceable calibration for atomic probe microscopes, scanning interferometers and other metrology instruments.

Remove the uncertainty:

picometer precision in nanometer measurements.

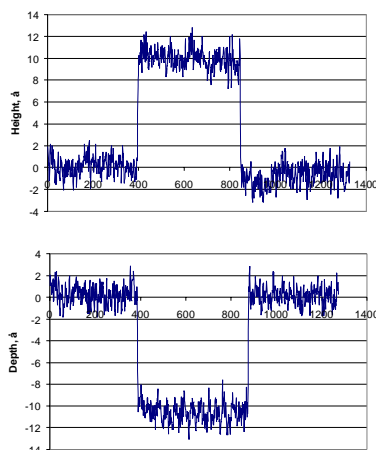
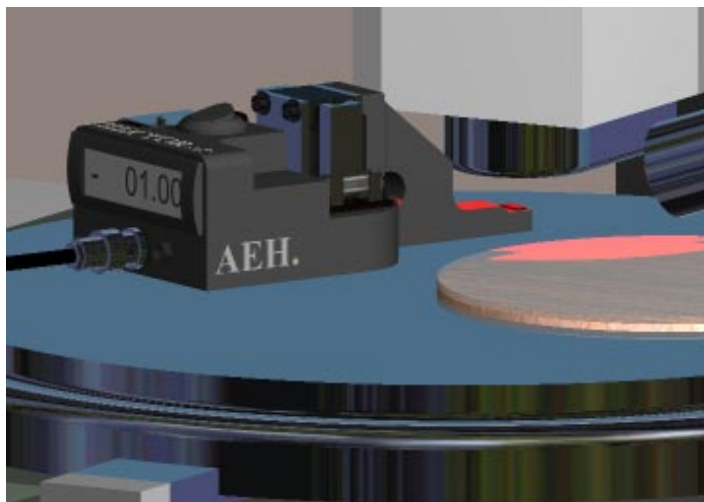
Alson E. Hatheway Incorporated

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“Hector-100” is a trademark of Alson E. Hatheway Inc.

Hector-100tm Calibrated Displacement Actuator (ASME B46.1-2002)



Nanometer-sized step and groove artifacts.

For Z-axis (height) **nanometer-scale** calibration of interferometers, profilometers and AFMs

Measured Performance

Artifact size range	-184.07 to +183.77 nm
Resolution	± 0.01 nm
Repeatability	<1.02 parts in 10,000
Linearity	<1.01 parts in 10,000
Stability	<5.7 parts in 10,000 per year

HECTOR-100

with electronic controller, batteries and hardwood instrument case: \$10,200.00

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